



INTEVAC

# Engineering Advanced Solar Cells with High Throughput Ion Implantation

**Intevac**

**Henry Hieslmair**



*Think Lean. Create Value.*

# Intevac Business Segments



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## Equipment Business

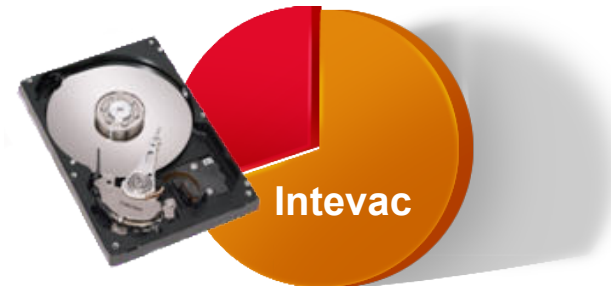
High Productivity Vacuum Process Solutions Since 1991

### Photovoltaic Cells



Enabling process solutions  
focus on efficiency and cost

### Hard Drive Media



Technology leader  
1 billion disks per year

## Photonics Business



Digital low-light sensor technology leader

# Intevac Equipment Product Family



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**200 Lean®  
Hard Drive Media**

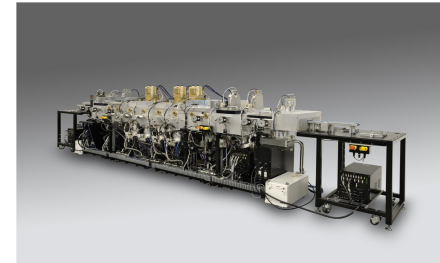


**Proven Reliability and  
Productivity**

**Solar**

- Higher cell efficiency
- Lower cost per watt
- Technology extendibility

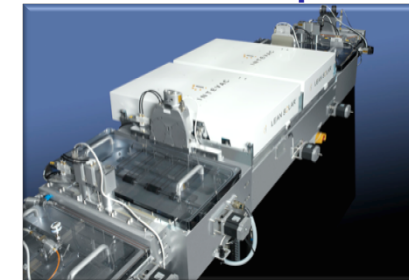
**NanoTexture™ Etch**



**ENERGi™ Ion Implant**



**Lean Solar™ Deposition**



**Universal platform addressing multiple advanced solar technologies**

# Ion Implantation for Solar



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## Benefits

- Tailoring of Phosphorus Profile
- Boron
  - Process simplification
  - Improved cost, no edge iso
- 1 sided doping
  - Process simplification
  - Improved cost, no edge iso
- Patterning of dopants
  - Selective emitter
  - Inter-digitated Back Contact Cells
- Uniformity & repeatability
  - Better binning
  - Better FF

## Drawback

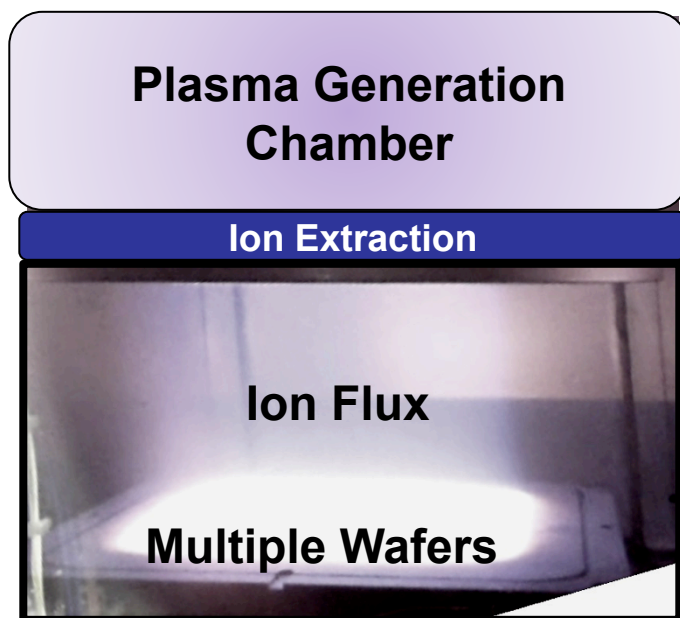
- Cost \$/Wp
  - Low throughput
  - High capital cost
- Patterning reduces throughput

# **ENERGi™** Designed for Solar



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## Continuous Flux Ion Beam



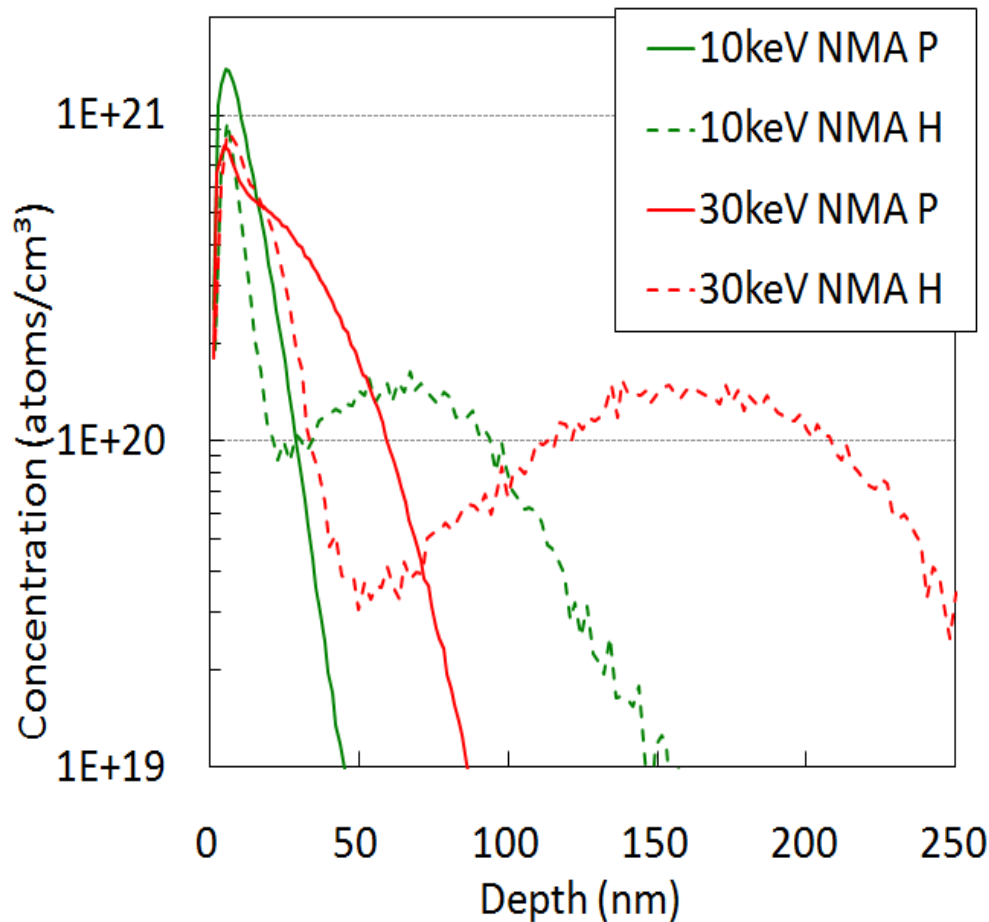
*Patent Pending*

- Lowest cost solution to ion implant
- 2400 wph throughput  
(Identical for P and N type implant)
- Wide energy range capability for customer required junction depths
- Simultaneous emitter formation  
(homogeneous and selective)
- Small footprint and ease of service

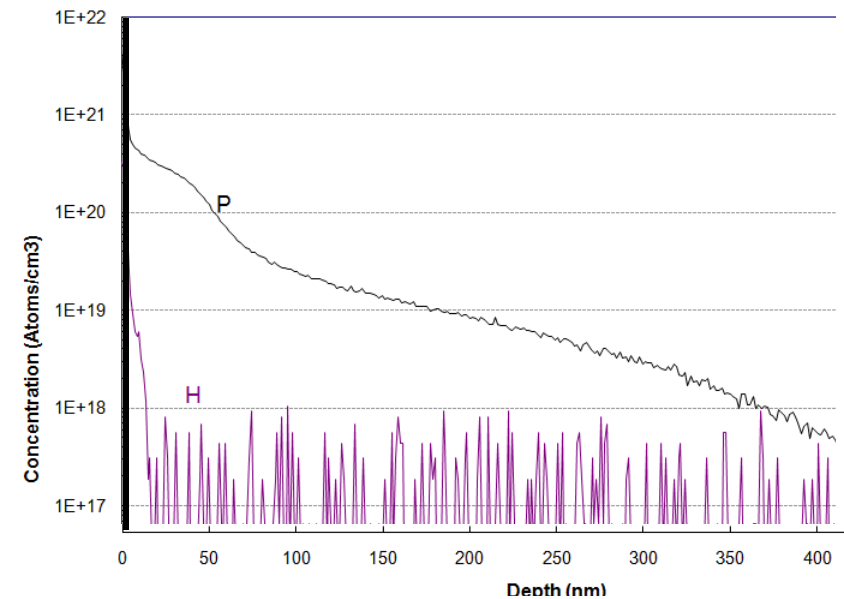
**ENERGi enables lowest cost of ownership solution for ion implant**



# Non-mass analyzed implant



- Co-implantation of H<sup>+</sup> from PH<sub>3</sub>
- Dose P  $\approx$  H
- H<sup>+</sup> low damage creation  
⇒ Electronic stopping
- H diffuses out after anneal

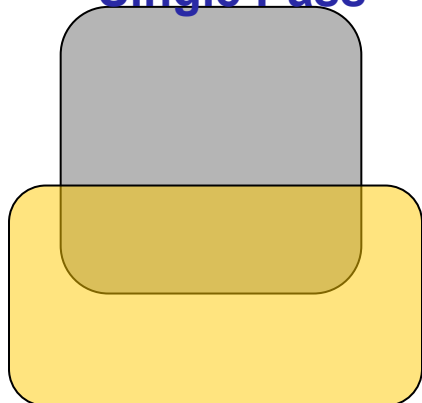


# ENERGi™ Continuous Flux System

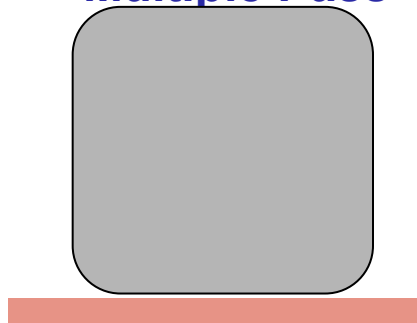


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Continuous Flux  
Single Pass



Ribbon (Beamline)  
Multiple Pass

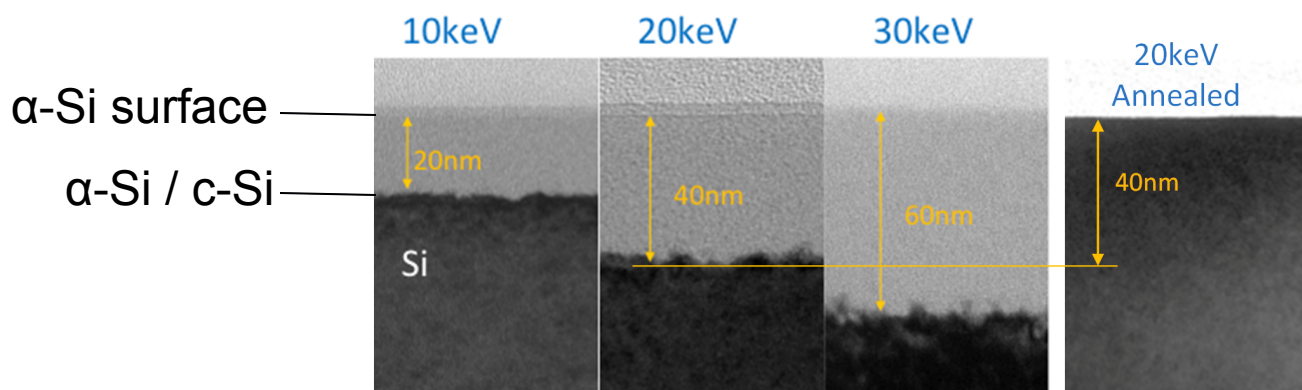


High quality amorphized layer via

- High continuous dose rate
- Single pass

Improves Solid Phase Epitaxial  
Re-growth (SPER)

- Low remaining defects



***ENERGi* Enables...**



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# TAILORING OF PHOSPHORUS PROFILE



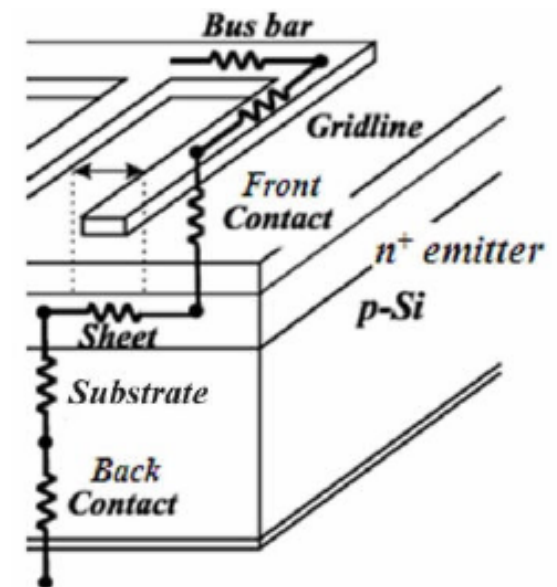
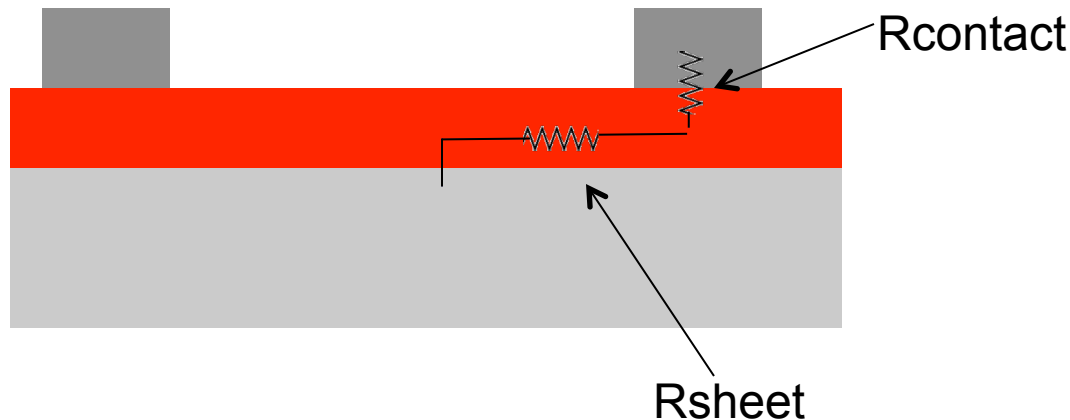


# Tailoring of Phosphorus Profile

- Sheet resistance
- Contact resistance
- Recombination

Series resistance & FF improves with high P doping and high near surface P dose

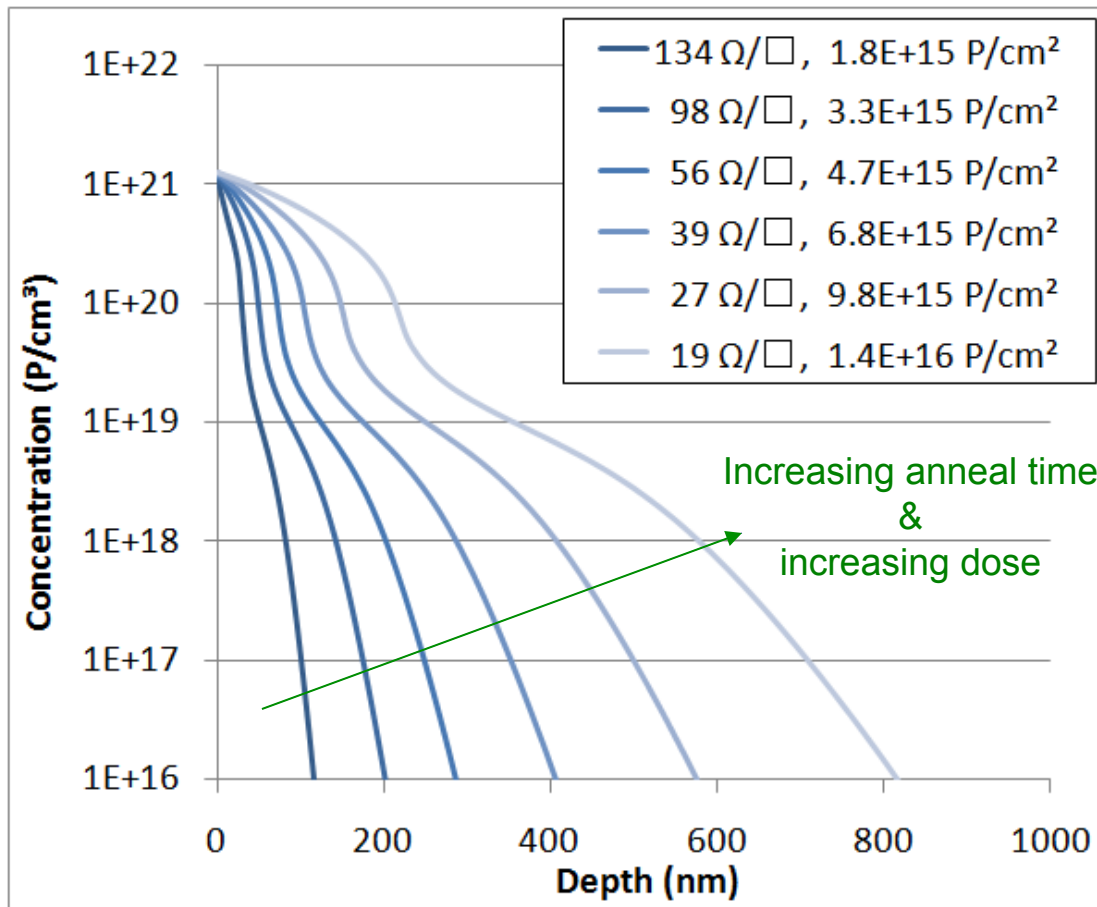
Voc and Jsc improve with low P doping and low P surface concentration.



# POCl<sub>3</sub> - Infinite P source



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Dose increases with time

POCl<sub>3</sub> has infinite source

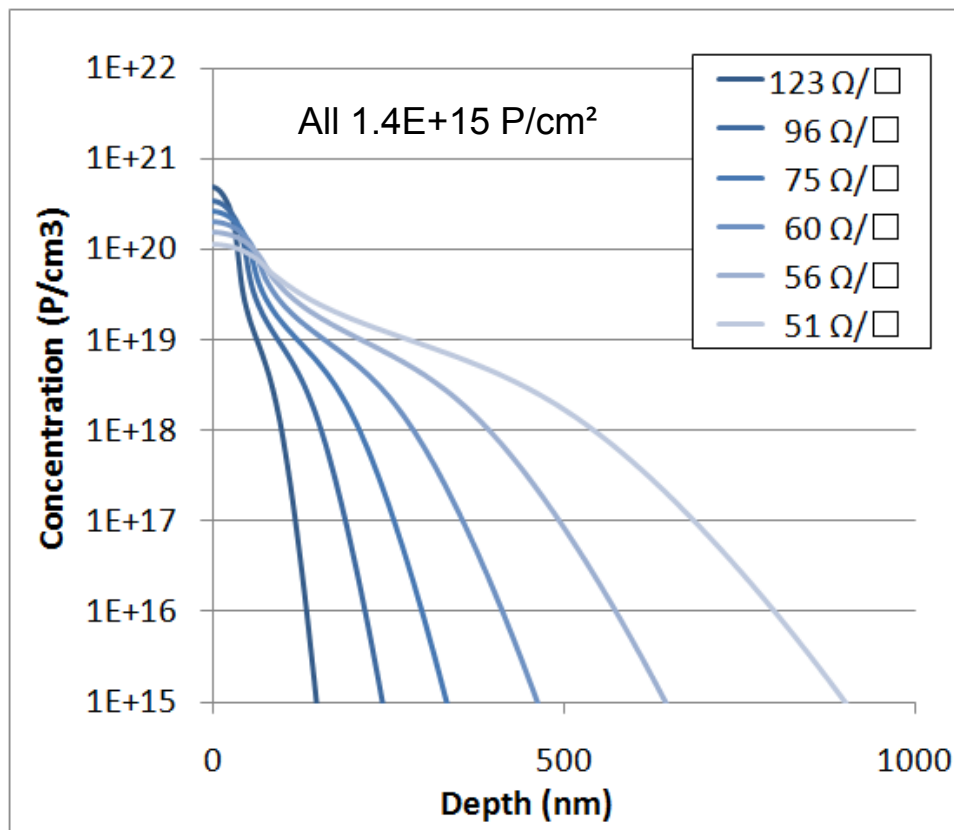
High surface concentration

Time and Ω/□ tightly linked.



# Fixed P dose

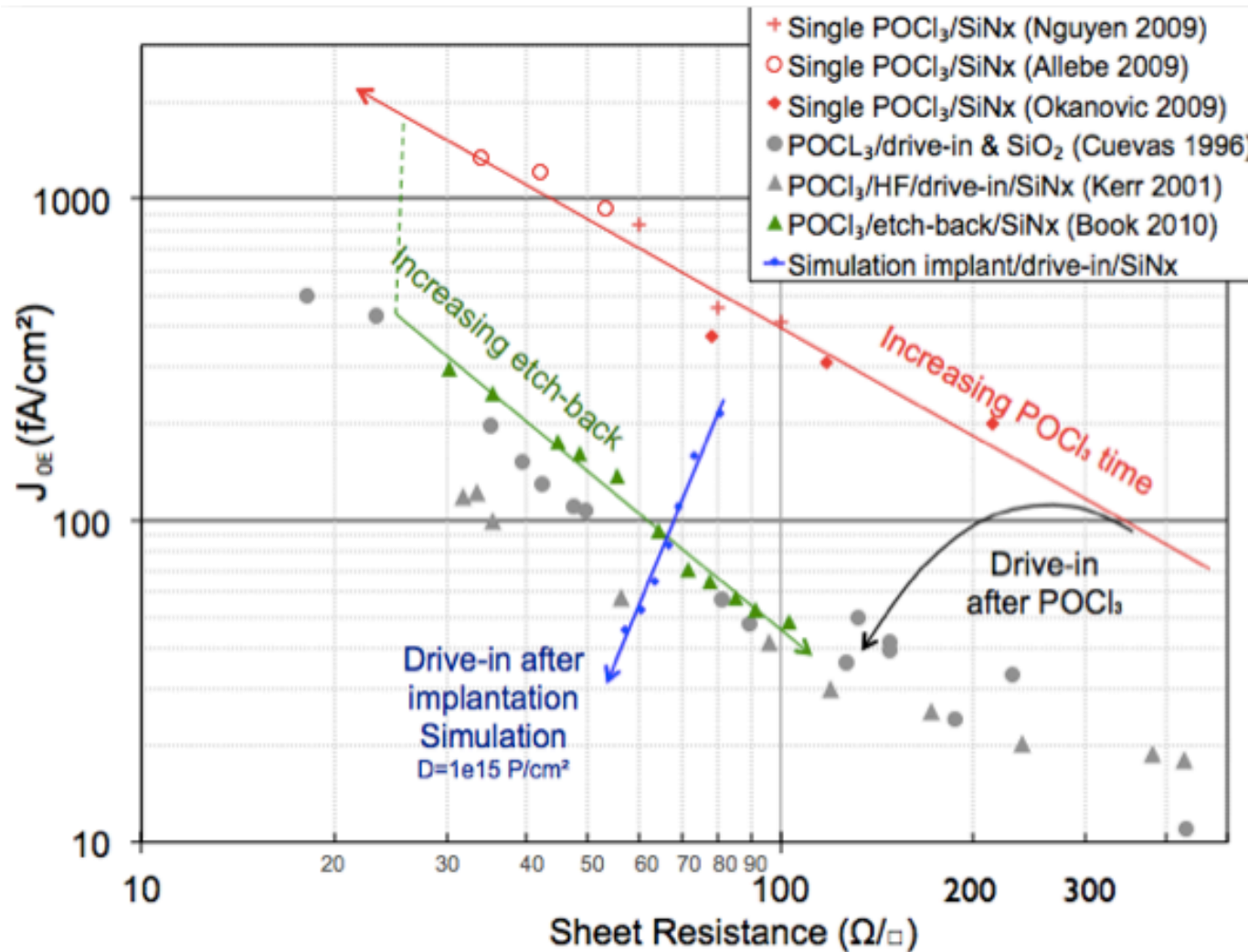
Profile shape changes lead to lower sheet resistance for fixed dose of P.



$$R_{sheet} = \frac{1}{q \int_0^{x_j} \mu_n(x) n(x) dx}$$



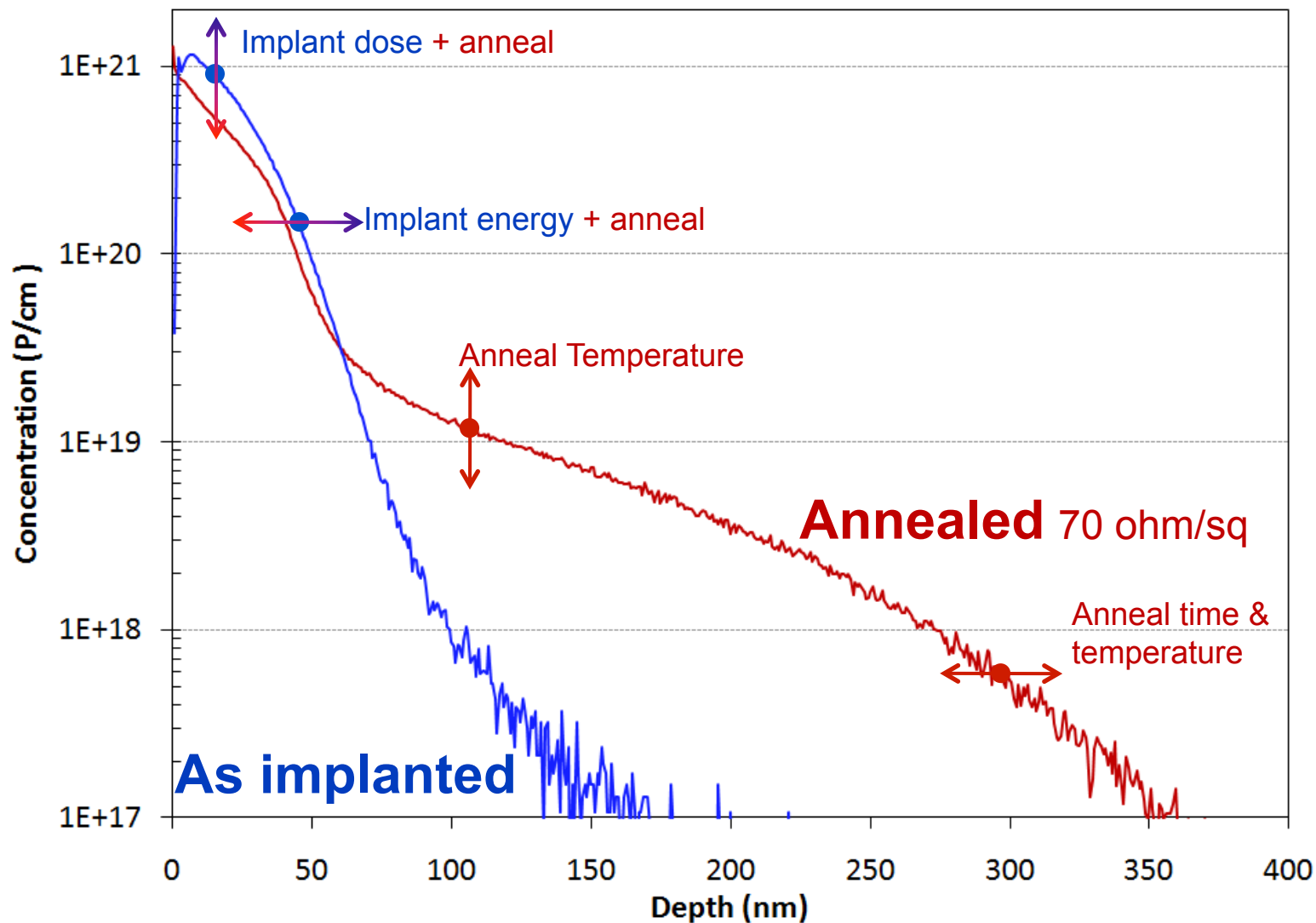
# Process paths



# Profile tailoring implanted finite P dose



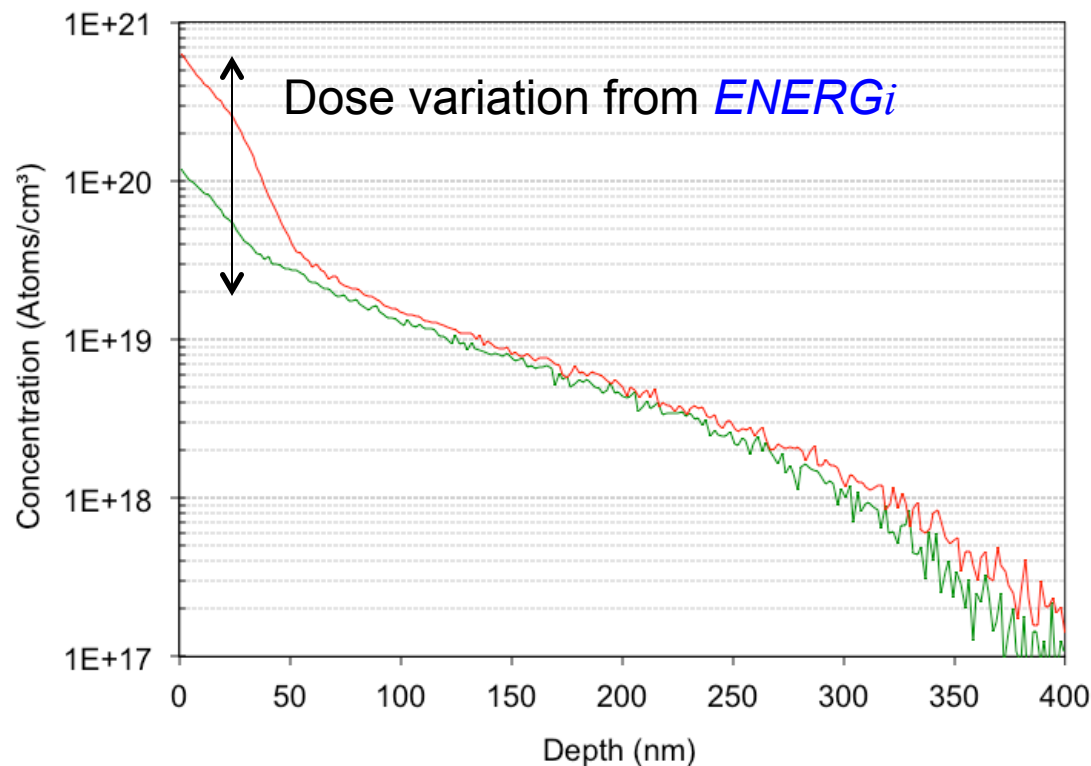
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# Tuning of surface P by implant dose



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Near surface dose can be manipulated by varying implant dose

Selective emitters have local regions of high dose and other regions of low dose

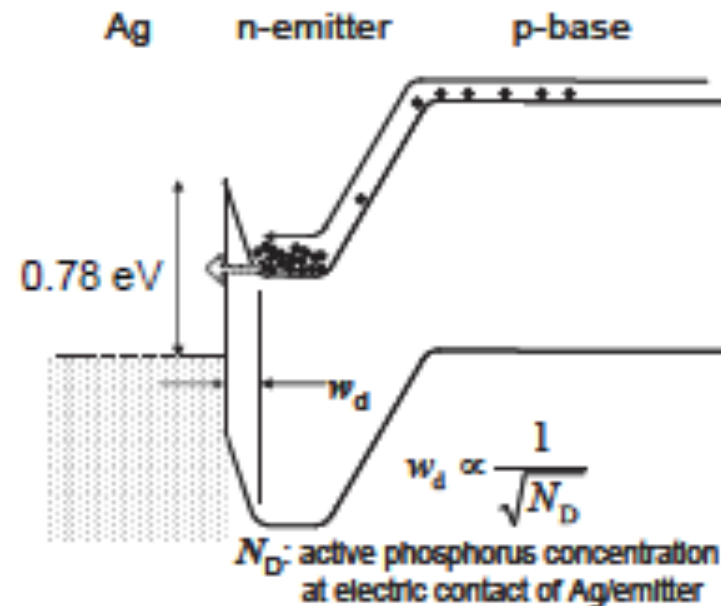
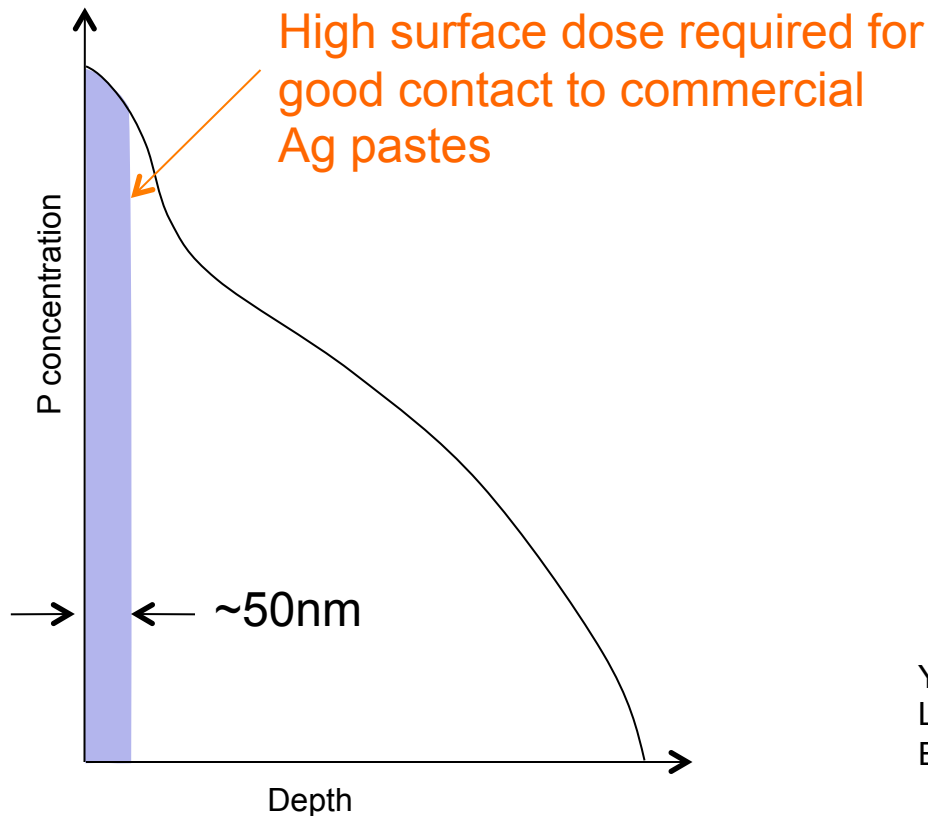


# CONTACT RESISTANCE

# Commercial Ag paste contacting



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Y. Komatsu et al, "Efficiency Improvement by Deeper Emitter with Lower Sheet Resistance for Uniform Emitters"  
Energy Procedia 8 (2011) 515-520

- Ag does not form silicide. Ag-Si contact is a tunneling junction
- Good tunneling required high/degenerate doping
- Tunneling has threshold behavior – Rc increases rapidly below threshold  $N_{Dose}$

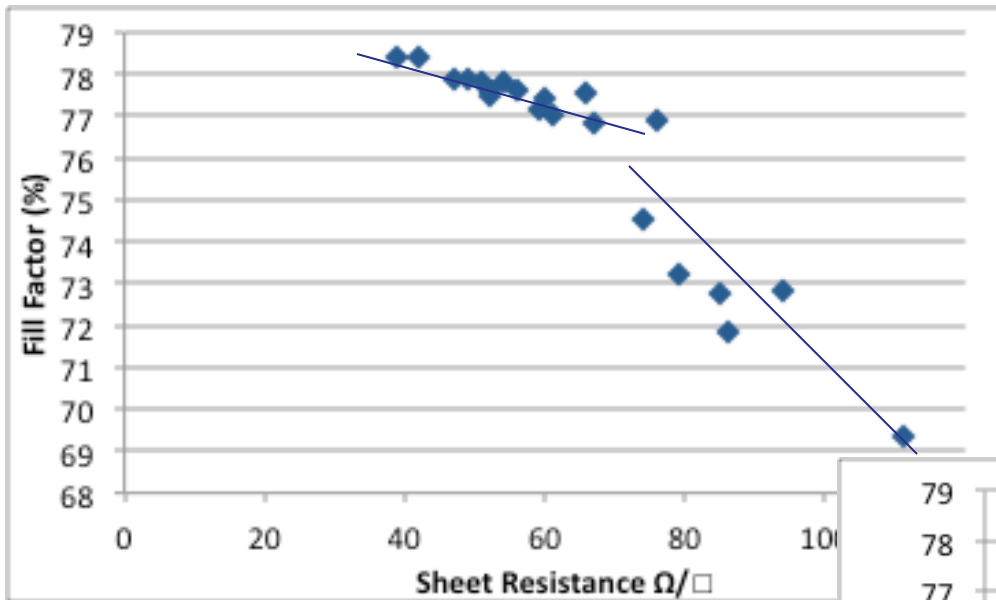




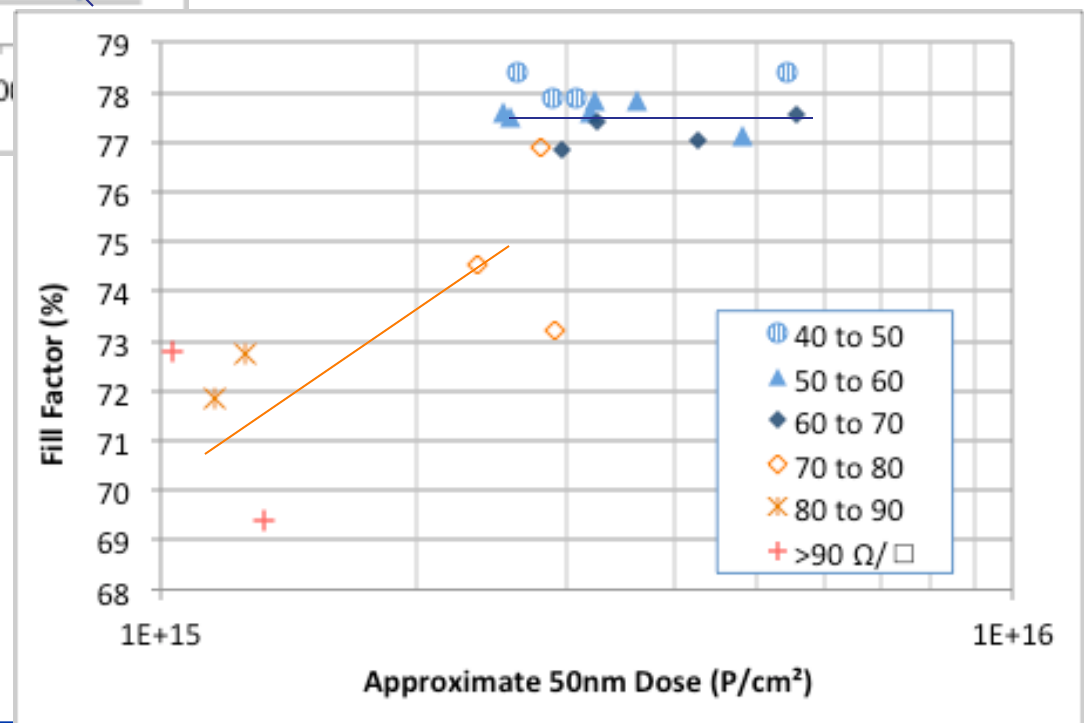
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# FF and Sheet Resistance from $\text{POCl}_3$

- Various  $\text{POCl}_3$  anneals
- Numerical integration of author's SIMS profiles
- Below  $\sim 2.5 \times 10^{15} \text{ P/cm}^2$  in first 50nm, FF drops off



Y. Komatsu et al, "Sophistication of Doping Profile Manipulation – Emitter Performance Improvement without Additional Processing Step"  
25<sup>th</sup> EuPVSEC Valencia, Spain 2010

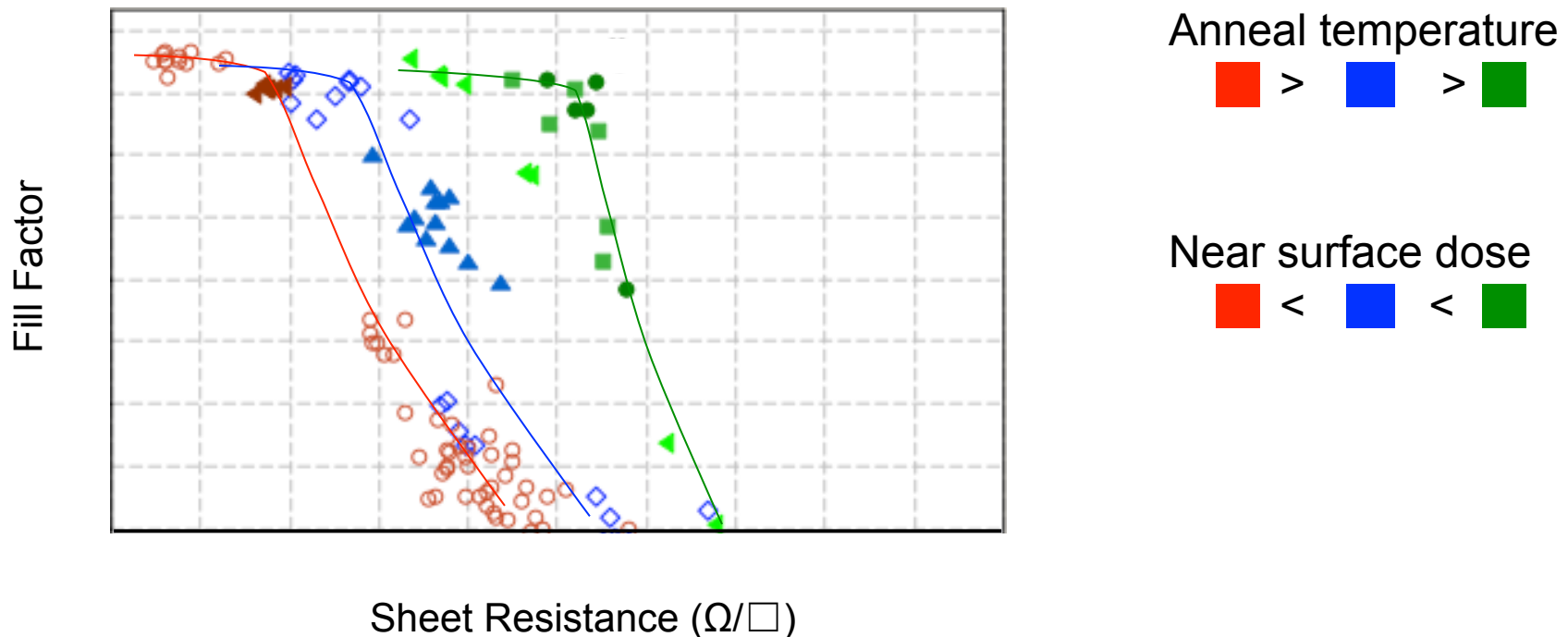


# Tailoring implanted emitters



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Implanted phosphorus with various annealing temperatures



Implant provides opportunity to finely tune cell process



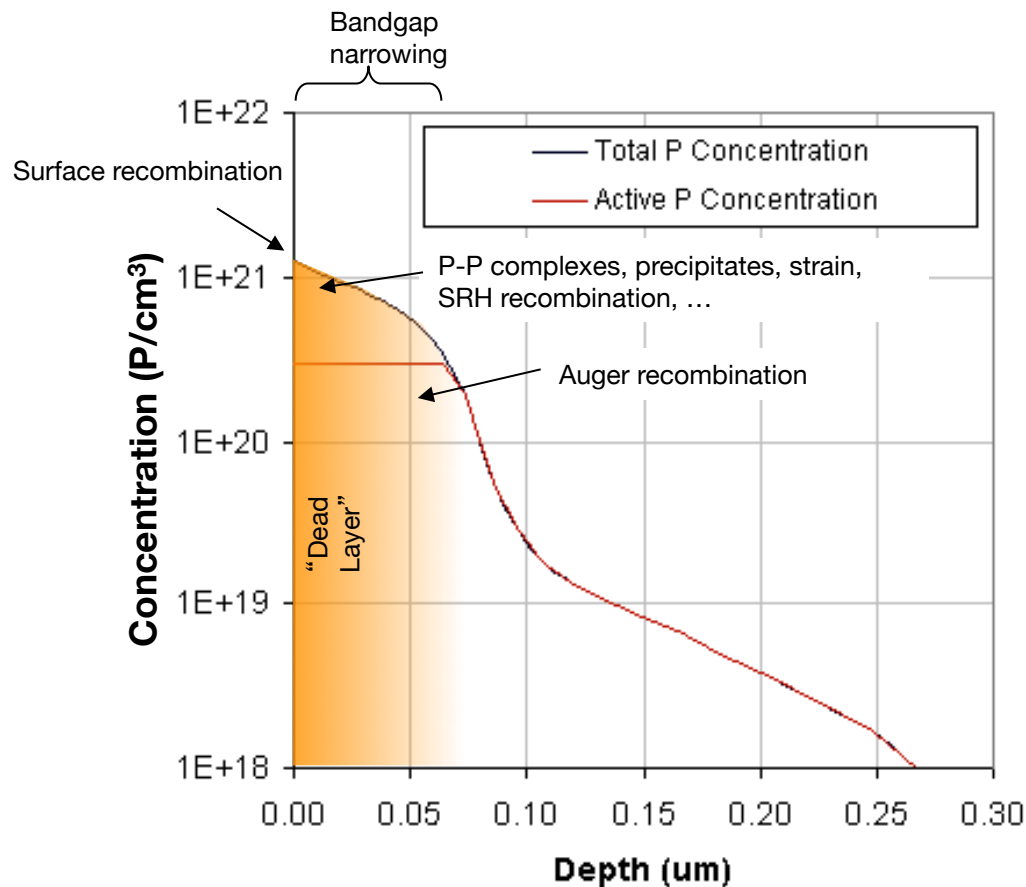
# RECOMBINATION

# Recombination mechanisms



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Lower recombination increases  $V_{oc}$



Surface recombination increases with surface concentration

Auger recombination at high P concentrations

SRH at precipitate/clusters above solubility concentration

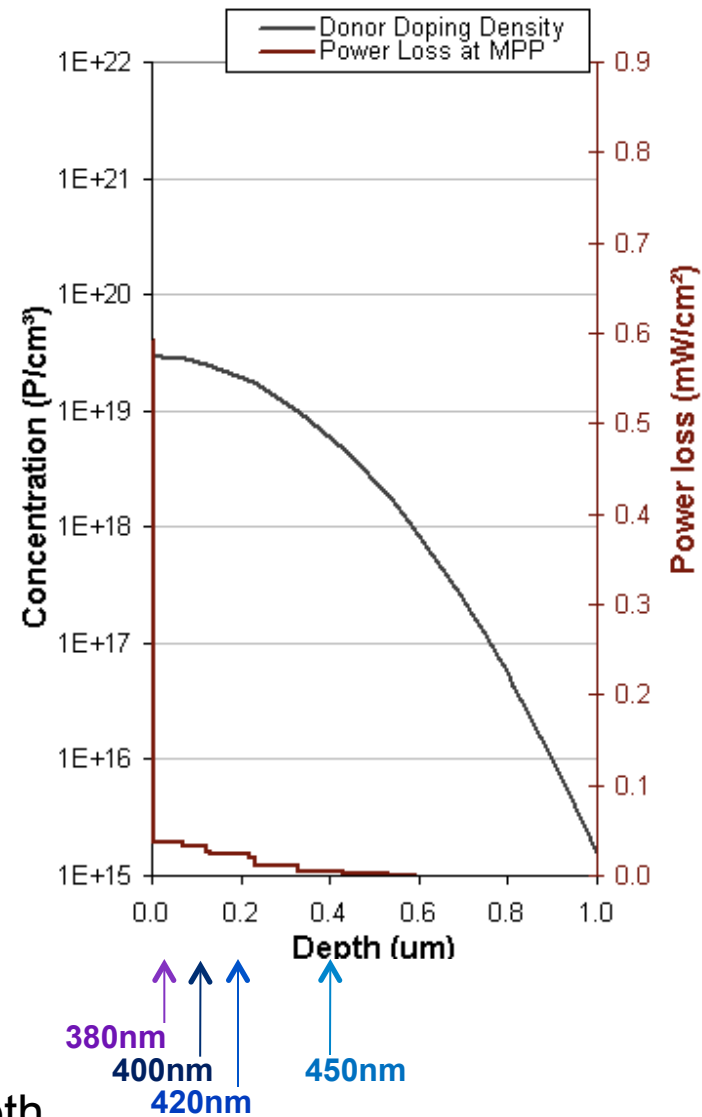
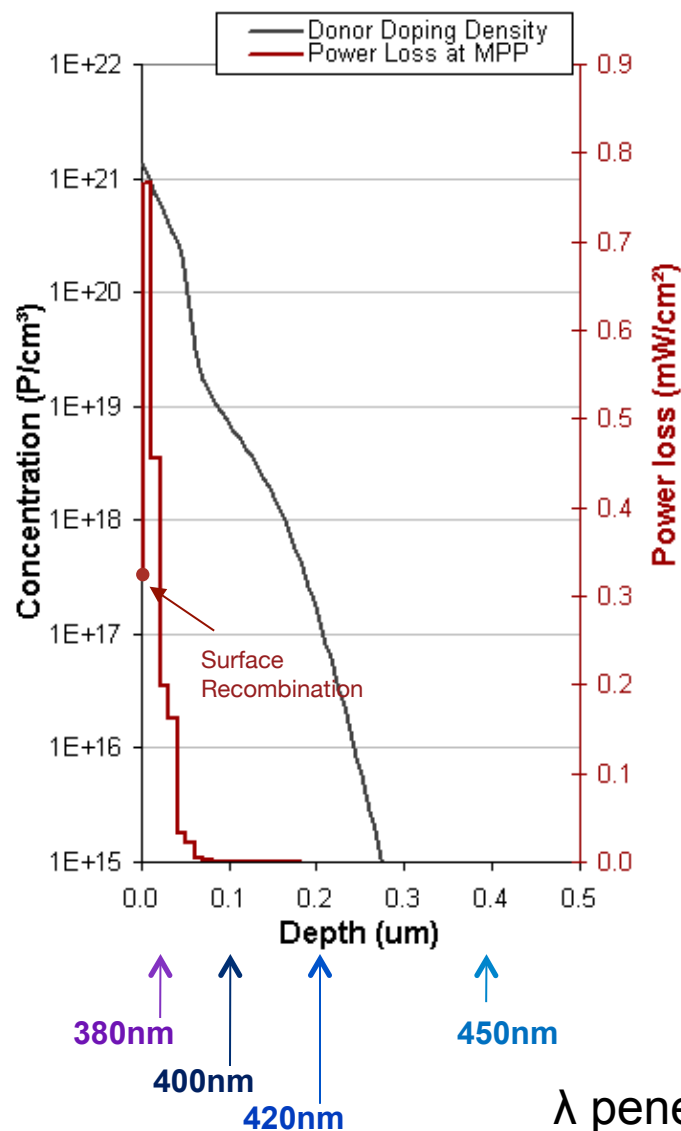
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# Simulations showing recombination loss in emitter



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Simulations of power losses (red) in two different  $70 \Omega/\square$  emitters (x-axis scale differs)

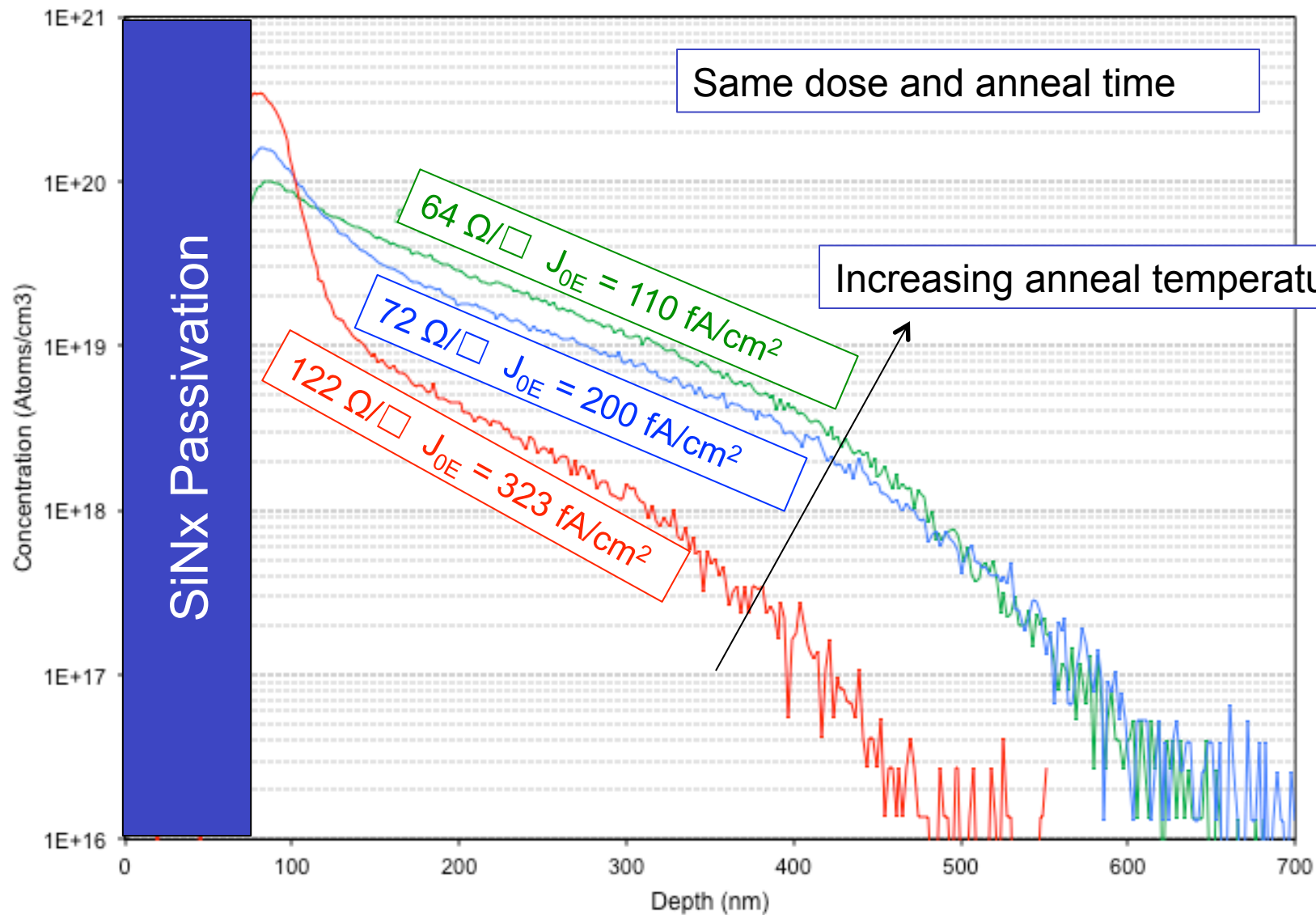


$\lambda$  penetration depth

# ENERGi manipulation of profiles



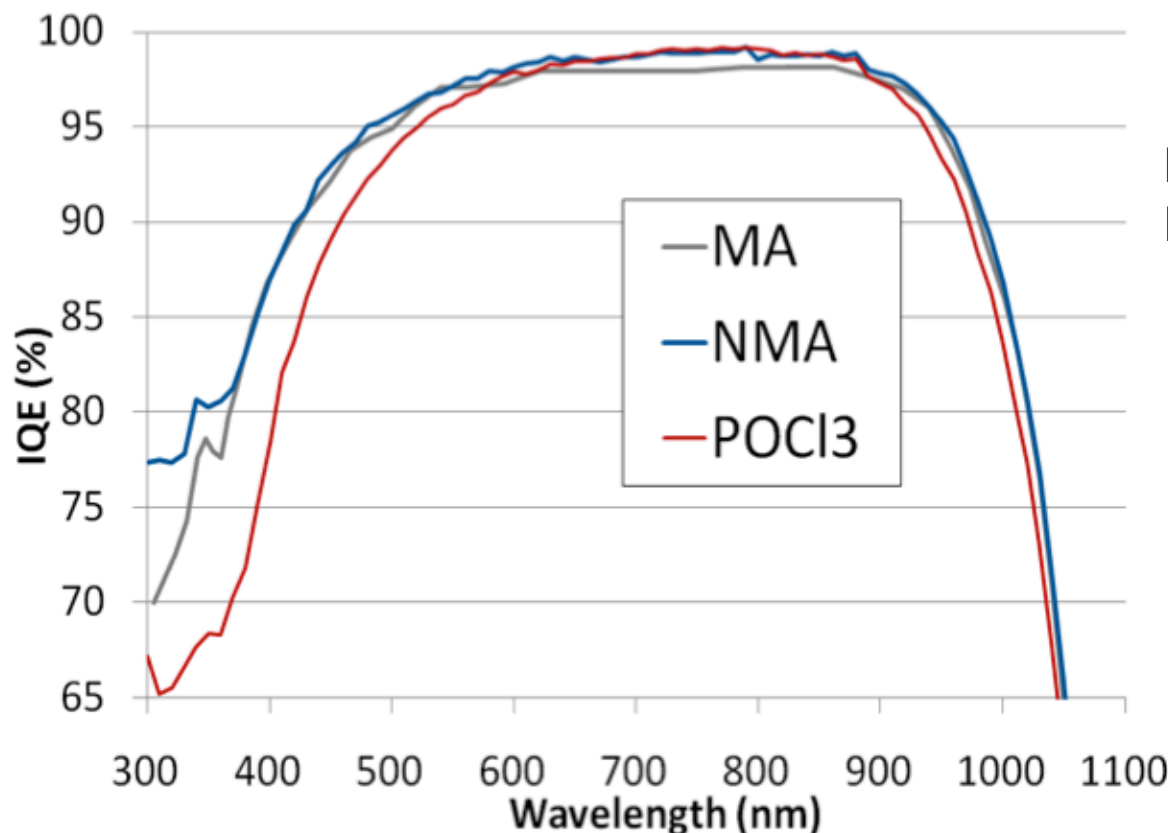
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# IQE Data Comparison for 60 $\Omega/\square$ Emitters



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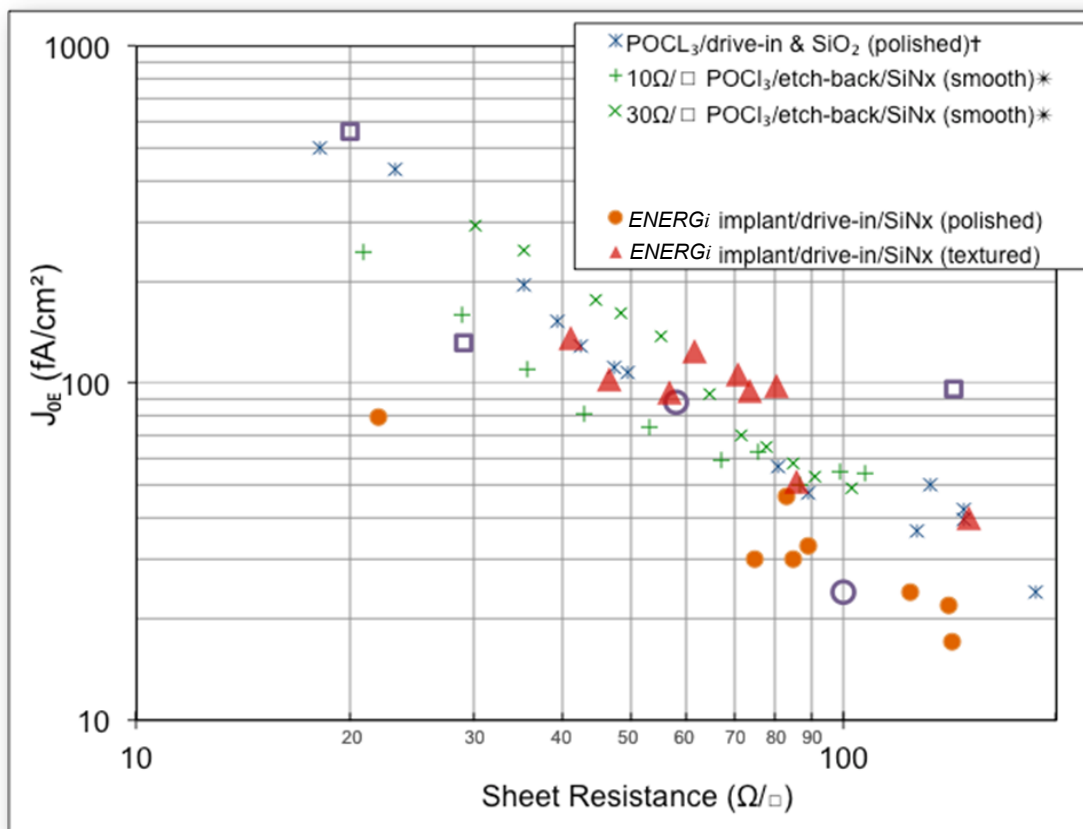


Mass Analyzed (MA)  
Non-Mass Analyzed (NMA)

**ENERGi** shows

- Improved IQE performance over traditional  $\text{POCl}_3$
- Equivalent performance to mass analyzed implant

MA IQE from A. Gupta, et al., High Efficiency Selective Emitter Cells Using In-Situ Patterned Ion-Implantation, 25th EUPVSEC, Valencia Spain, 2010.





# Schematic illustration of emitter optimization

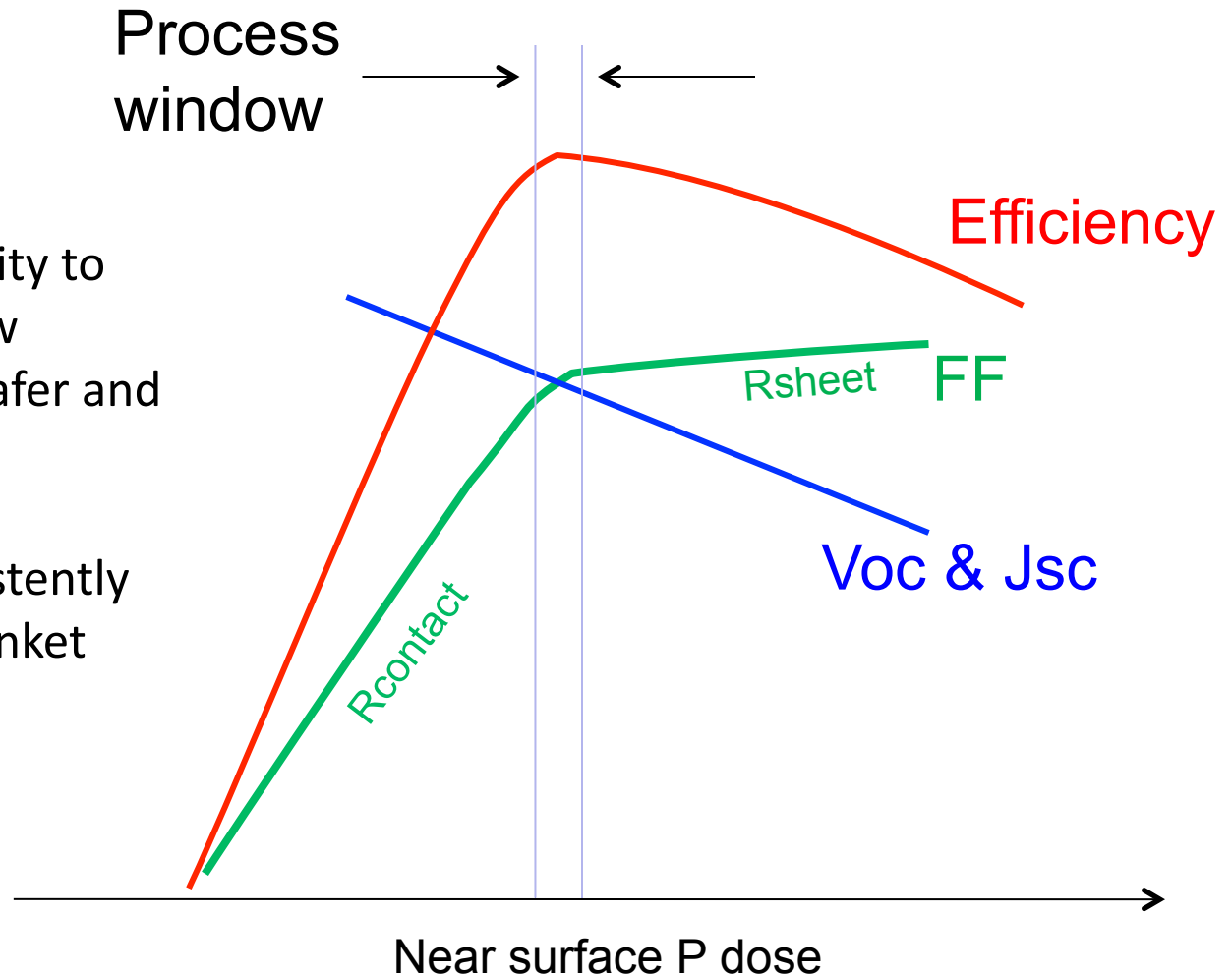


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Process  
window

High efficiency requires ability to consistently achieve a narrow process window – within wafer and wafer to wafer.

Implantation helps to consistently achieve same P dose on blanket emitters



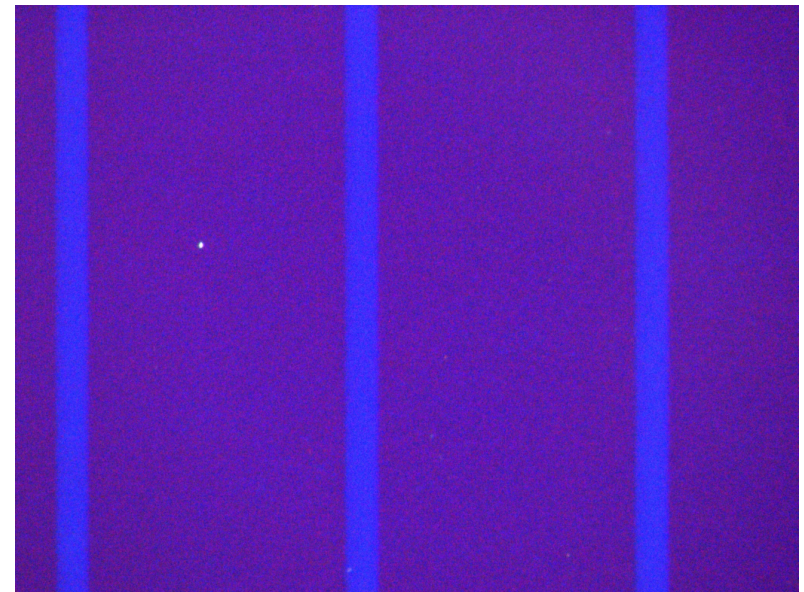
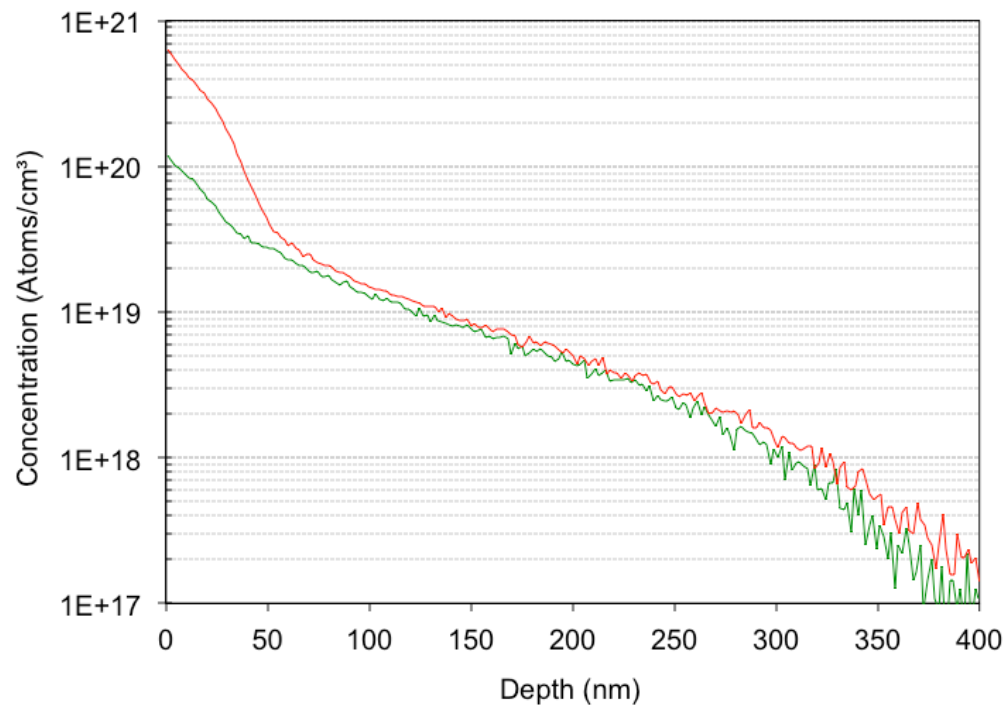


# **SELECTIVE EMITTERS with *ENERGi* implantation**



## Selective emitters

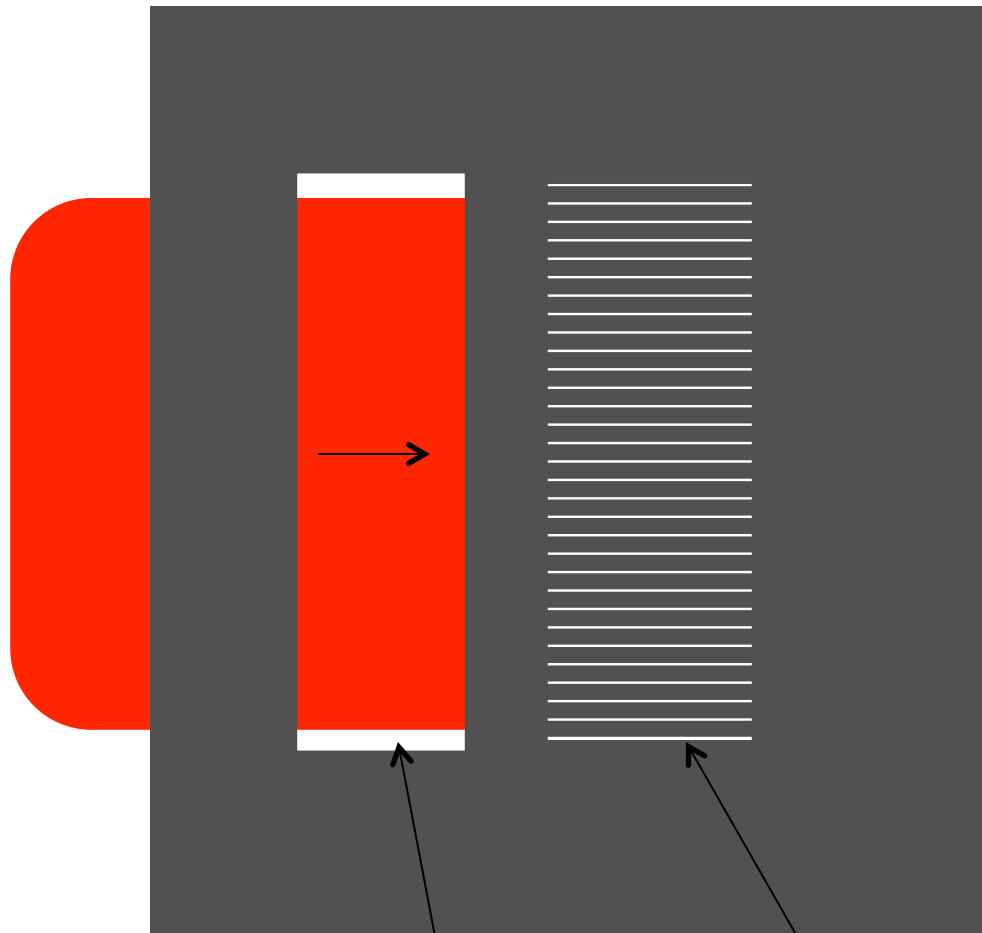
High P dose only under metallization for low  $R_{\text{contact}}$   
Low P dose elsewhere for high  $V_{\text{oc}}$ ,  $J_{\text{sc}}$



Optical image of *ENERGi*  
single pass implanted and  
annealed SE



# One pass SE using shadow mask



ENERGi schematic of single pass selective emitter doping.

Two zones of shadow mask create homogenous and selective doping

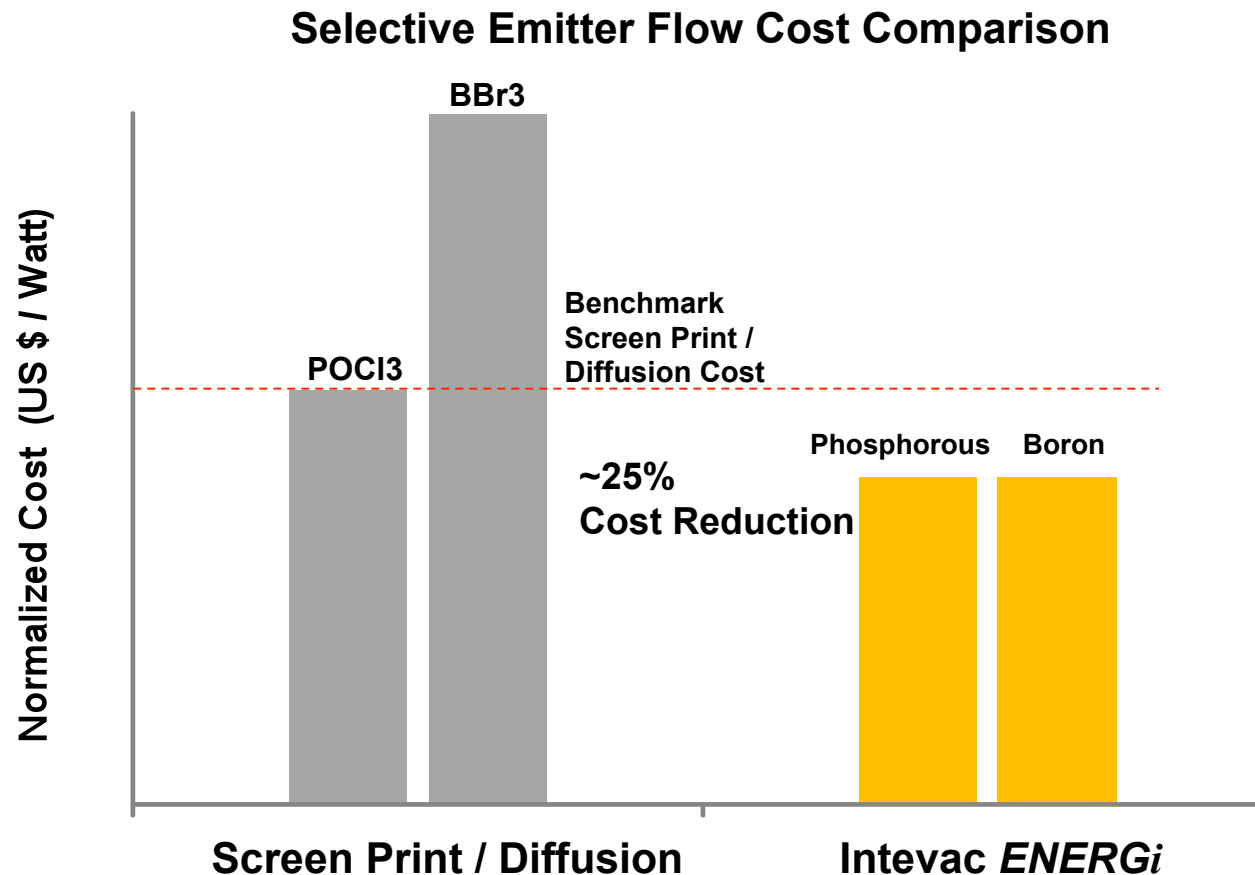
Selective emitter openings

Homogenous emitter opening

# Cell Manufacturing CoO Reduction



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***ENERGi*<sup>™</sup> enables lower cost of ownership  
for N and P-type cells**

Cost of ownership components: Capital, Gas, Utility, Floor space, Consumables, Labor

**Proprietary**

**Think Lean. Create Value.**

# Enabling Ion Implant Solution



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## Lean Solar *ENERGi*



- Improved emitter profiles for higher cell efficiency
- Capable of simultaneous selective and homogeneous emitter in one system
- Single sided implant enabling reduced process steps
- High productivity, lower COO than screen print / diffusion flow for selective emitter
- Enables high efficiency N-type cells

# Visit Intevac



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**VISIT US AT INTERSOLAR 2012**  
**MOSCONE CENTER • SAN FRANCISCO**

Booth 5870 • North Hall  
July 10 - 11, 10 a.m. - 5 p.m.  
July 12, 10 a.m. - 4 p.m.

Customer Meetings  
West Hall • Level 2  
Room 2012

POWERING INNOVATION.  
DELIVERING VALUE.

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**END**